

January 2009
UniFETTM

FDD5N53/FDU5N53 N-Channel MOSFET 530V, 4A, 1.5 Ω

Features

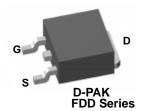
- $R_{DS(on)} = 1.25\Omega$ (Typ.)@ $V_{GS} = 10V$, $I_D = 2A$
- Low gate charge (Typ. 11nC)
- Low C_{rss} (Typ. 5pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · RoHS compliant



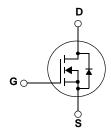
Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pluse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power suppliesand active power factor correction.







MOSFET Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted*

Symbol		Parameter		FDD5N53/FDU5N53	Units
V_{DSS}	Drain to Source Voltage			530	V
V_{GSS}	Gate to Source Voltage			±30	V
	Drain Current	-Continuous (T _C = 25°C)		4	А
ID	Drain Current	-Continuous (T _C = 100°C)		2.4	A
I _{DM}	Drain Current	- Pulsed	- Pulsed (Note 1)		Α
E _{AS}	Single Pulsed Avalanche Energy (Note 2		(Note 2)	256	mJ
I _{AR}	Avalanche Current		(Note 1)	4	Α
E _{AR}	Repetitive Avalanche Energy		(Note 1)	4	mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	4.5	V/ns
D	Dawer Dissipation	(T _C = 25°C)		40	W
P_{D}	Power Dissipation	- Derate above 25°C		0.3	W/°C
T _J , T _{STG}	Operating and Storage Tempe	Operating and Storage Temperature Range			°C
T _L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

Thermal Characteristics

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.4	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	110	C/VV

Units

Max.

Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD5N53	FDD5N53TM	D-PAK	380mm	16mm	2500
FDD5N53	FDD5N53TF	D-PAK	380mm	16mm	2000
FDU5N53	FDU5N53TU	I-PAK	=	=	70

Test Conditions

Min.

Тур.

Electrical Characteristics

Parameter

Off Characteristics						
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{\circ}C$	530	-	-	V
$\Delta BV_{DSS} \ \Delta T_J$	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	-	0.6	-	V/°C
1	Zero Gate Voltage Drain Current	$V_{DS} = 530V, V_{GS} = 0V$	-	-	1	μА
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 424V, T_{C} = 125^{\circ}C$	-	-	10	μΑ
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±100	nA

On Characteristics

Symbol

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 2A$	-	1.25	1.5	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 40V, I_D = 2A$ (Note 4)	-	4.3		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 05V V 0V	-	480	640	pF
C _{oss}	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ 	-	66	88	pF
C _{rss}	Reverse Transfer Capacitance	1 - 111112	-	5	8	pF
Q _{g(tot)}	Total Gate Charge at 10V		-	11	15	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DS} = 400V, I_{D} = 5A$	-	3	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	V _{GS} = 10V (Note 4, 5	-	5	-	nC

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			-	13	36	ns
t _r	Turn-On Rise Time	$V_{DD} = 250V, I_{D} = 5A$		-	22	54	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25\Omega$		-	28	66	ns
t _f	Turn-Off Fall Time		(Note 4, 5)	-	20	50	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current			-	4	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	16	Α
V_{SD}	Drain to Source Diode Forward Voltage V	_{GS} = 0V, I _{SD} = 4A	-	-	1.4	V
t _{rr}	Reverse Recovery Time V	$I_{GS} = 0V, I_{SD} = 5A$	-	300	-	ns
Qrr	Reverse Recovery Charge d	$II_F/dt = 100A/\mu s$ (Note 4)	-	1.8	-	μС

- 1: Repetitive Rating: Pulse width limited by maximum junction temperature 2: L = 32mH, I_{AS} = 4A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C 3: I_{SD} \leq 4A, $di/dt \leq$ 200 A/μ s, $V_{DD} \leq$ 8V $_{DSS}$, Starting T_{J} = 25 $^{\circ}$ C 4: Pulse Test: Pulse width \leq 300 μ s, Duty Cycle \leq 2% 5: Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

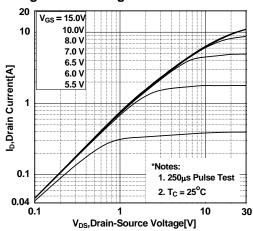


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

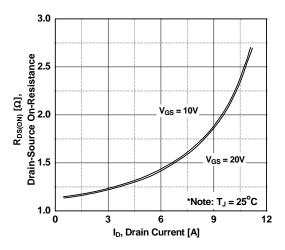


Figure 5. Capacitance Characteristics

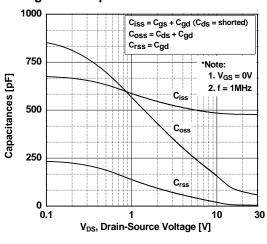


Figure 2. Transfer Characteristics

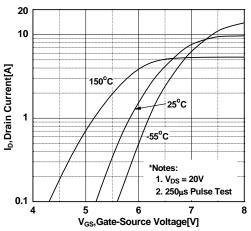


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

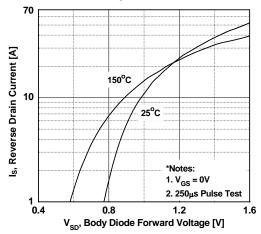
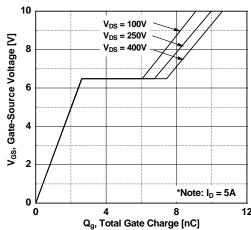


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

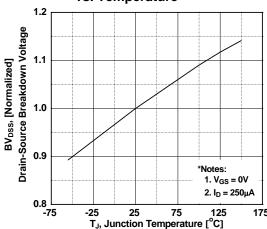


Figure 8. On-Resistance Variation vs. Temperature

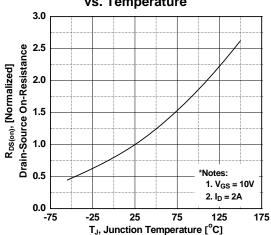


Figure 9. Maximum Safe Operating Area

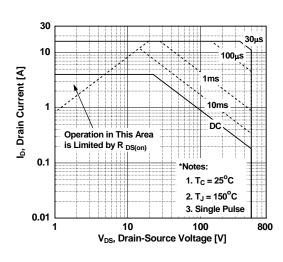


Figure 10. Maximum Drain Current vs. Case Temperature

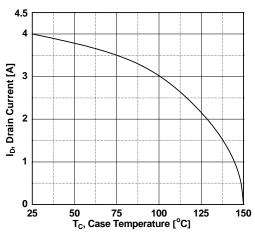
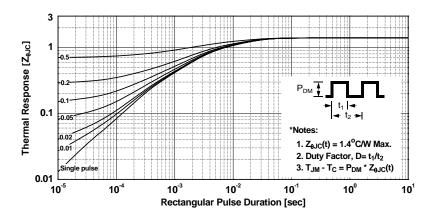
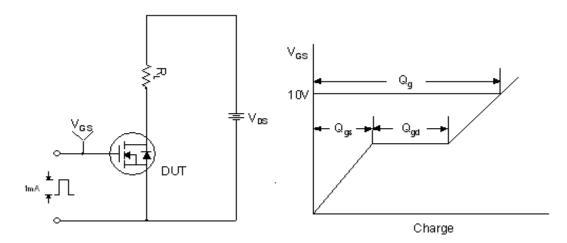


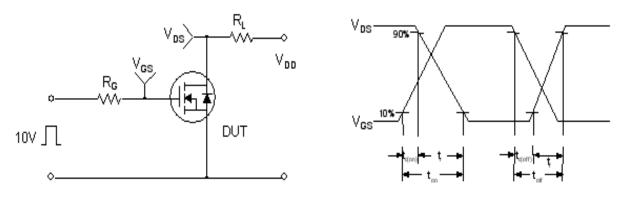
Figure 11. Transient Thermal Response Curve



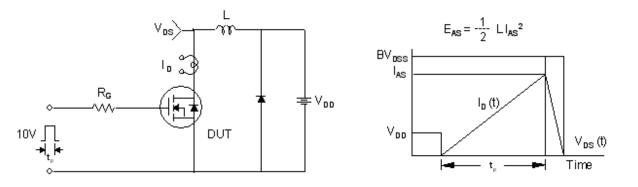
Gate Charge Test Circuit & Waveform



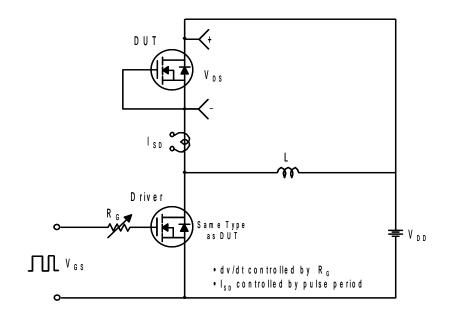
Resistive Switching Test Circuit & Waveforms

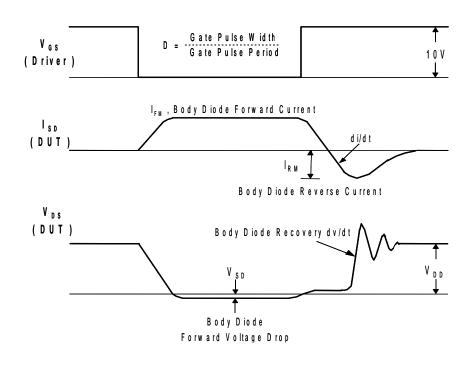


Unclamped Inductive Switching Test Circuit & Waveforms



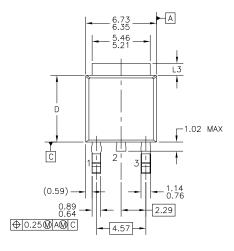
Peak Diode Recovery dv/dt Test Circuit & Waveforms

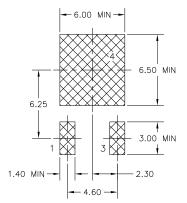




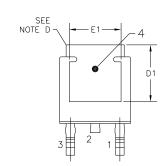
Mechanical Dimensions

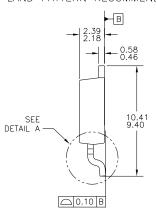
D-PAK

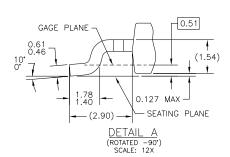




LAND PATTERN RECOMMENDATION







- NOTES: UNLESS OTHERWISE SPECIFIED

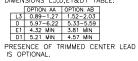
 A) ALL DIMENSIONS ARE IN MILLIMETERS.

 B) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA & AB, DATED NOV. 1999.

 C) DIMENSIONING AND TOLERANCING PER ASME '14.5M-1994.

 D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.

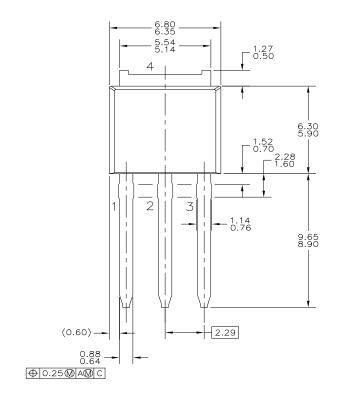
 E) DIMENSIONS L3,D,E1&D1 TABLE:

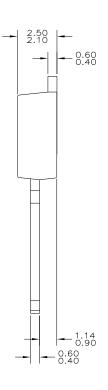


Dimensions in Millimeters

Mechanical Dimensions

I-PAK







Dimensions in Millimeters





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